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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-106004	Application No. 10/807,273	
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.		
		Filing Date March 24, 2004	Group Art Unit 2871	

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	closure Statement	Applicant Shunpei Yamazaki et al.		
(Use several sheets if necessary)		Filing Date March 24, 2004	Group Art Unit 2871	

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